

ADHESIVES PROPERTIES FOR SUCCESSFUL PHOTONIC PACKAGING

Garian Lim – Strategic Business Development Manager



Outline

- ▶ DELO introduction
- ▶ Silicon photonics bonding task and adhesive applications
- ▶ Optical coupling evaluation
- ▶ Wafer level photonics coupling solution
- ▶ Summary



HQ near Munich, Germany



€ 229 M. Revenues in 2024



1,000 employees



2nd production in Malaysia under construction



15 offices across 11 countries



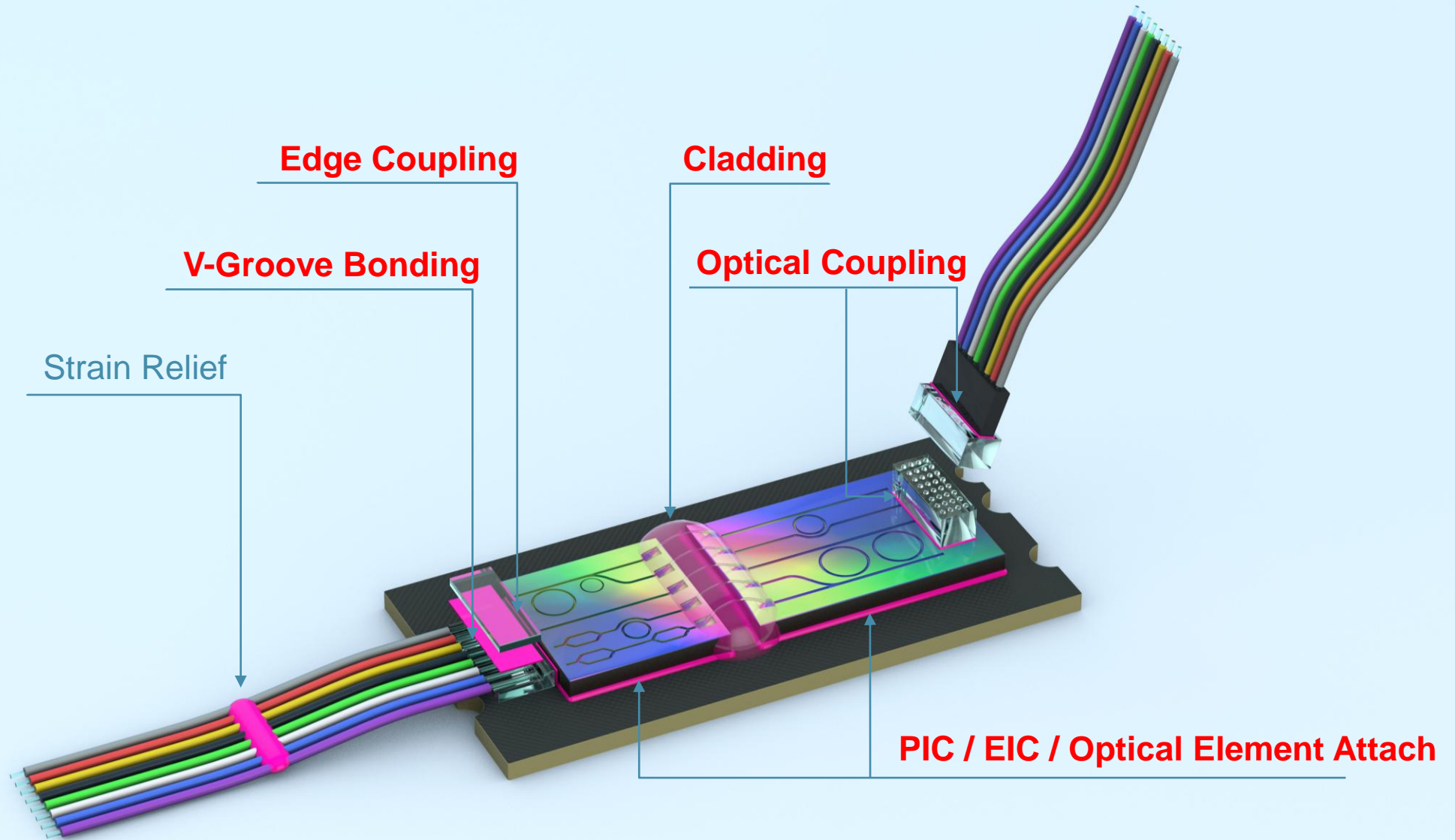


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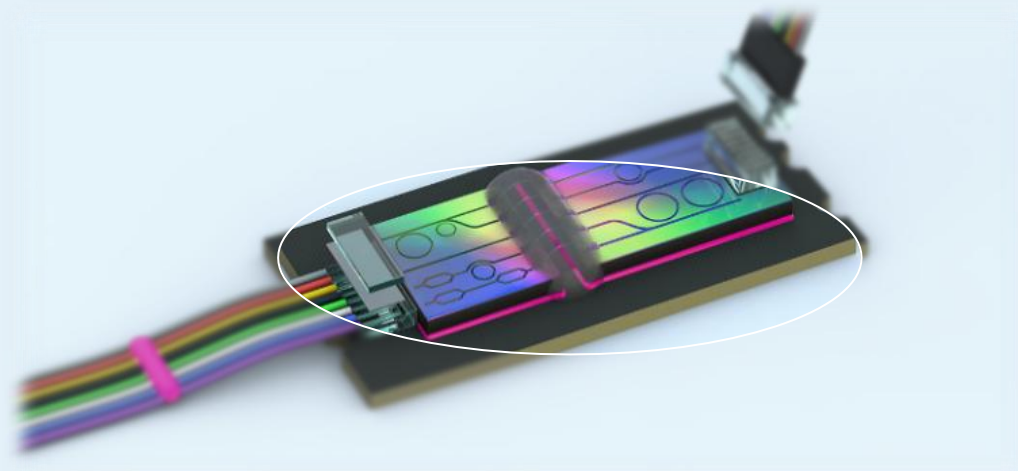


PIC Packaging - Bonding Tasks





PIC/EIC/Optical Element Attach



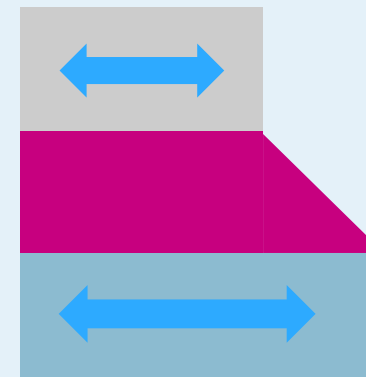
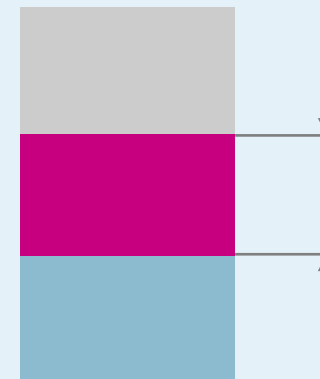
Challenges

- ▶ CTE mismatching
- ▶ Small bondline thickness (keep R_{th} low)
- ▶ Lateral die dimensions mm to cm

Adhesive key properties

- ▶ Flexibility (Young's modulus and elongation at tear)
- ▶ Adhesion strength
- ▶ Thermal conductivity

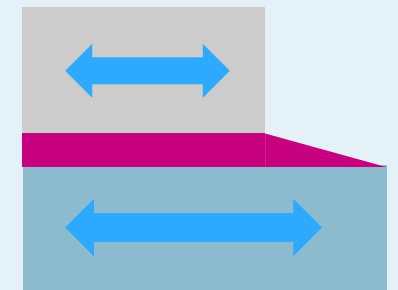
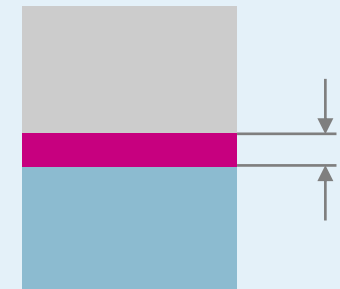
High BLT



Elongation

Low deformation @ adhesive

Low BLT

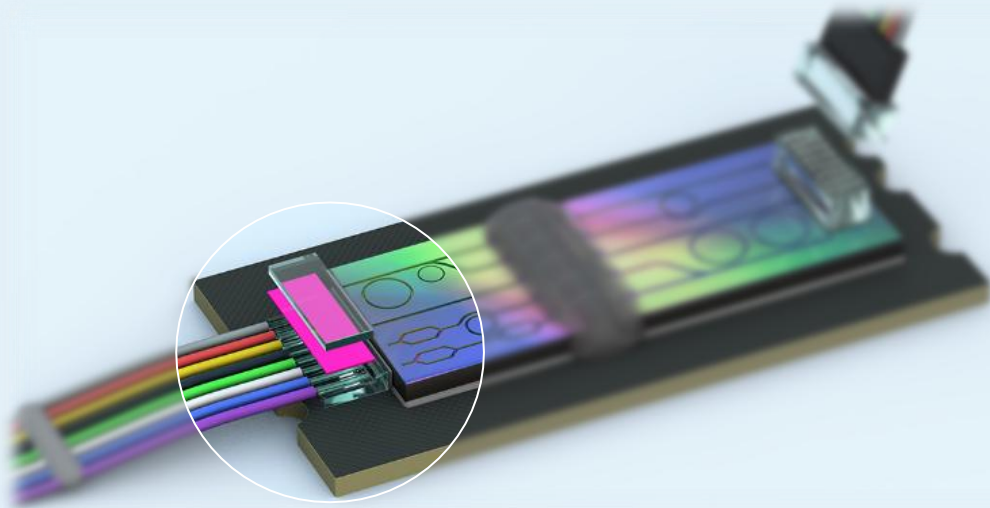


Elongation

High deformation @ adhesive



V-Groove Bonding



Lidless FA

Challenges

- ▶ Wetting and flowing
- ▶ (Thermo)mechanical stress

Adhesive key properties

- ▶ Viscosity
- ▶ CTE
- ▶ Shrinkage
- ▶ Young's Modulus
- ▶ Water absorption

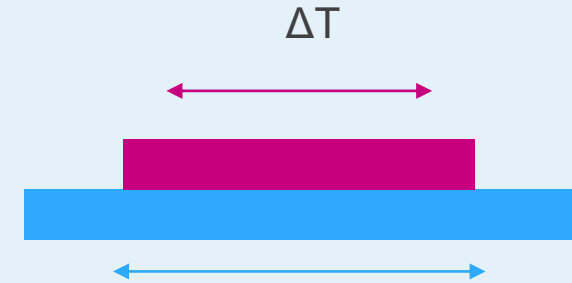
Regular FA

Challenges

- ▶ Wetting and flowing
- ▶ Delamination

Adhesive key properties

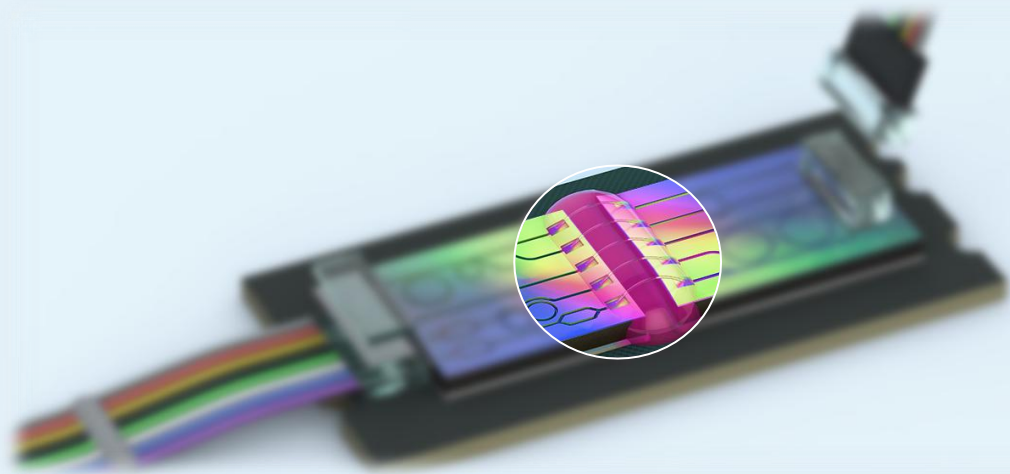
- ▶ Viscosity
- ▶ Adhesion
- ▶ Water absorption



$$\sigma_T = (\alpha_{adhesive} - \alpha_{substrate}) * E_{adhesive} * \Delta T$$

- ▶ Stress on bonding interface
 - CTE, YM, Tg (because CTE 2 > CTE 1), shrinkage
 - low modulus → less stress
 - low shrinkage → less stress
 - Adjusted (low) CTE → less stress

Cladding

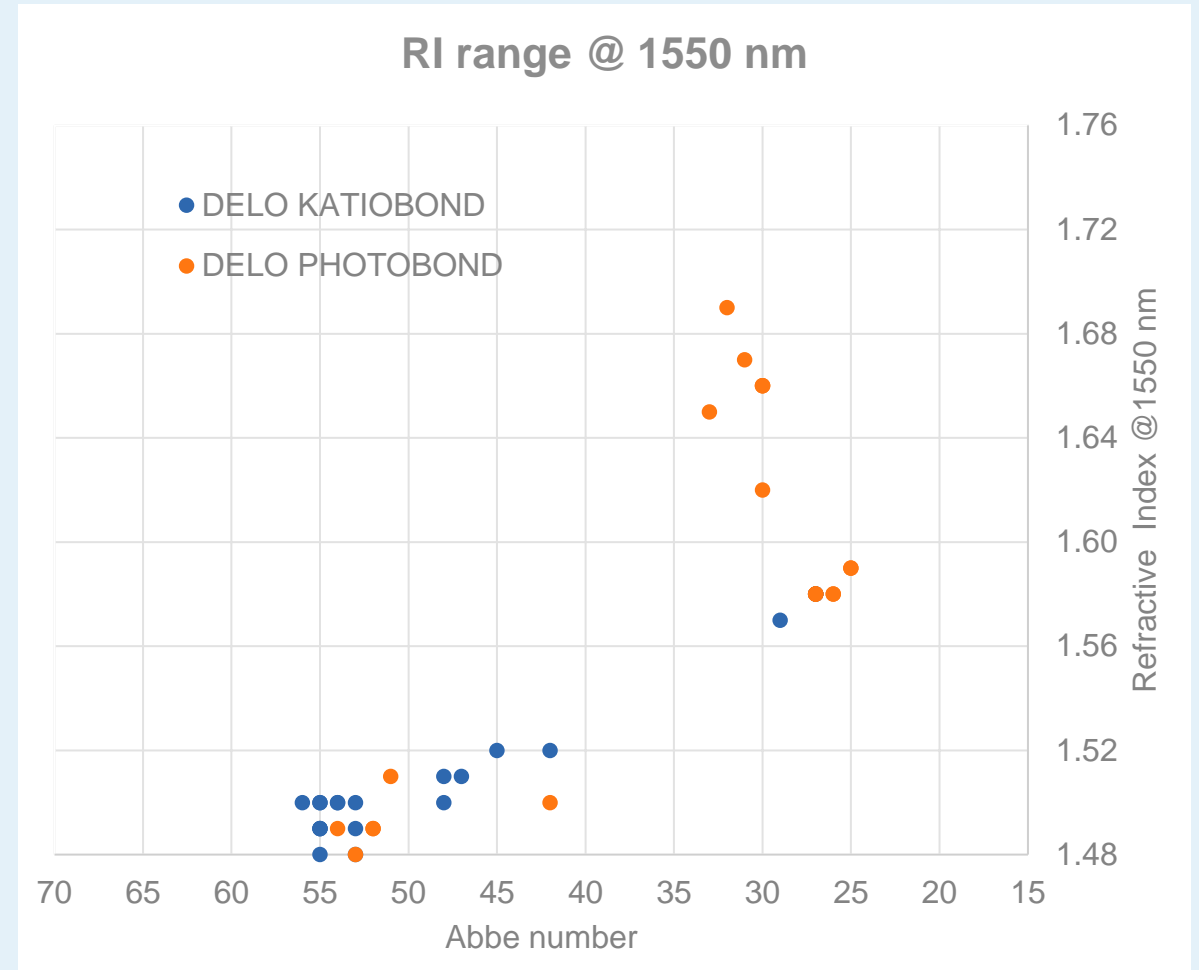


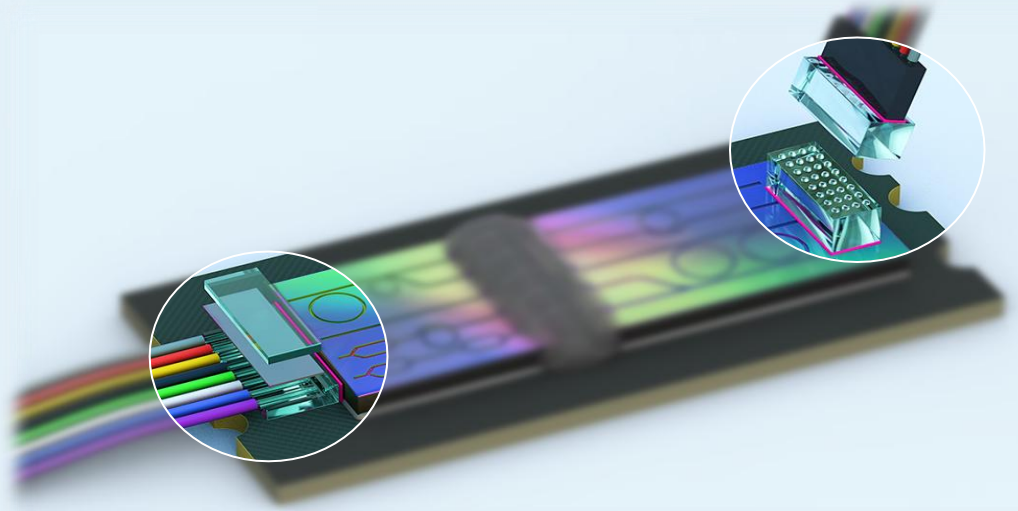
Challenges

- ▶ (Thermo) mechanical stress
- ▶ Reliable optical properties

Adhesive key properties

- ▶ Shrinkage
- ▶ CTE
- ▶ Young's modulus
- ▶ Refractive index
- ▶ Water absorption

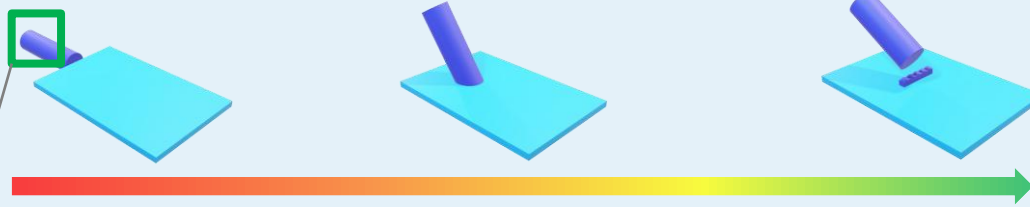




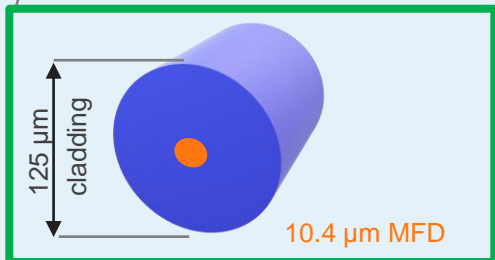
Edge coupling

Grating coupling

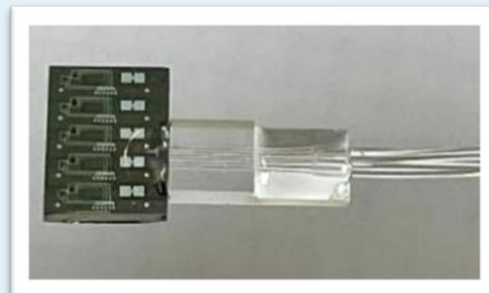
+ microlenses



Active Alignment tolerances



cross section of a SM fiber



Edge coupling FAU to PIC

Active Alignment Process

- ▶ Highly precise alignment → low & even shrinkage, homogenous fillet (shrinkage, viscosity)
- ▶ High Processing speed → fast curing, low thermal drift, low post curing (curing speed, enthalpy, fast build up of adhesion, max. curable layer thickness)

Performance & Reliability

- ▶ High Coupling efficiency → low signal attenuation (transmission, refractive index)
- ▶ Reflow compatibility → no movement or degradation after reflow (T-resistance (optical properties), T_g, CTE)
- ▶ TC → no delamination (CTE, bonding strength, Young's Modulus)
- ▶ THT → no delamination, no swelling (bonding strength, water absorption)



Photonic Packaging Material Challenge



Mechanical properties

- Thermal expansion
- Young's modulus
- Glass transition temperature

Processing

- Shrinkage control
- UV curing
- Active Alignment



Optical properties

- Index of refraction
- Transmission
- Optical stability

Reliability

- Reflow stability
- Dimensional stability
- Adhesion to substrate

➔ Photonic assembly different from classical packaging assembly



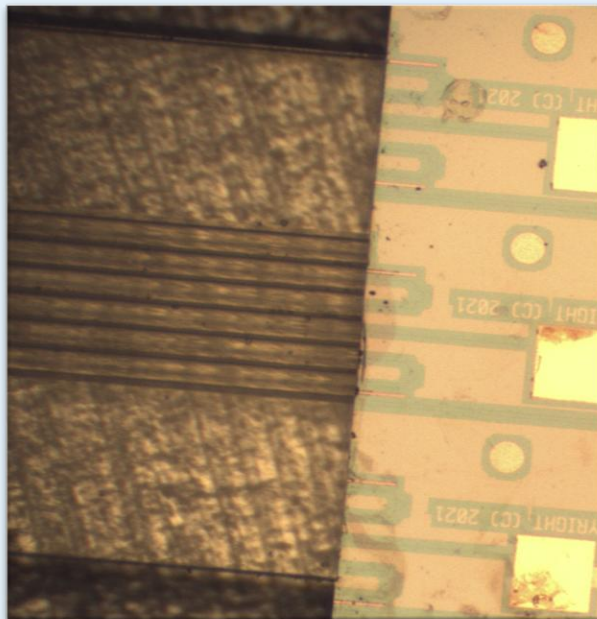


Assembling the parts: Working with a fillet



Without fillet

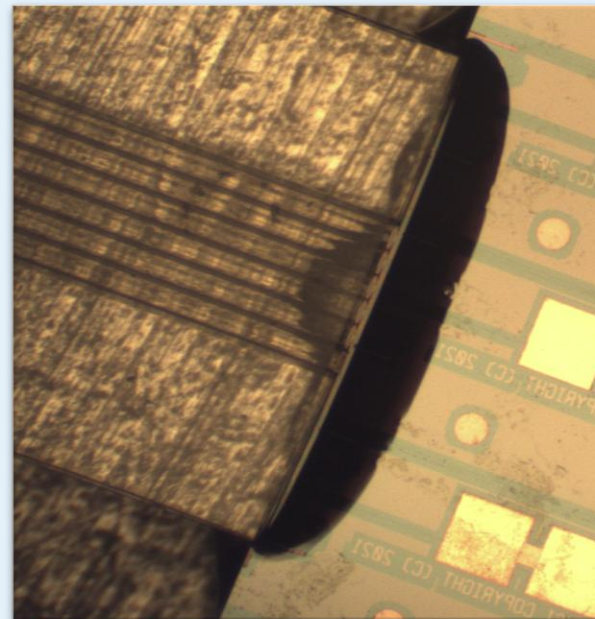
- ✓ Low effect by shrinkage
- ✗ Low bonding area → low bonding strength
- ✗ Hard to realize



Edge coupling without fillet

With fillet

- ✗ Significant effect of shrinkage
- ✓ Supporting bonding strength



Edge coupling with fillet

01083

General Targets

- ▶ Low shrinkage
- ▶ Low CTE
- ▶ High T_g
- ▶ **High transmission**
- ▶ **RI matching**
- ▶ **Reliable bonding strength**
- ▶ **Fast curing**

Mechanical properties Optical properties

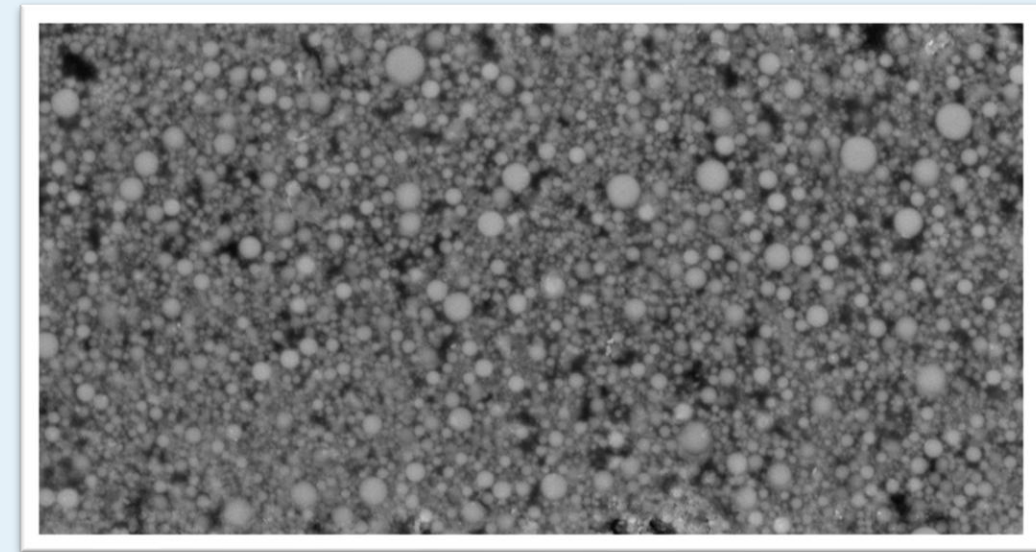


Processing Reliability



Adding fillers to resin influences mechanical, optical and rheological properties:

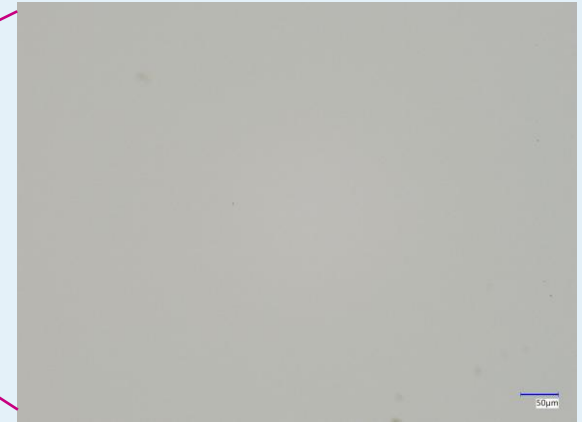
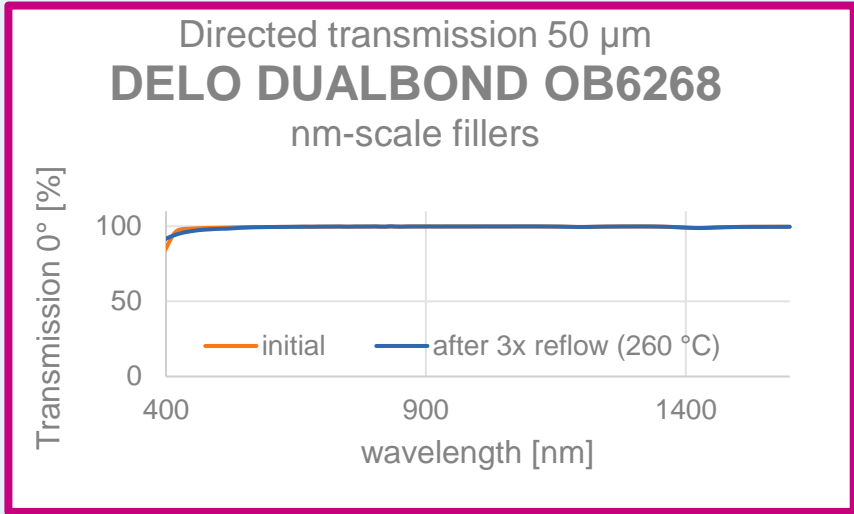
- ▶ Shrinkage → Reducing polymer content
($V_{\text{total}} = V_{\text{polymer}} + V_{\text{fillers}}$)
 - ▶ CTE
 - ▶ Enthalpy (less exothermic energy)
 - ▶ Refractive Index
 - ▶ Transmission
 - ▶ Young's Modulus & hardness
 - ▶ Viscosity
 - ▶ Adhesion
-
- ▶ Typical fillers: SiO_2 , TiO_2 , ZrO , Ag, Ni, polymer



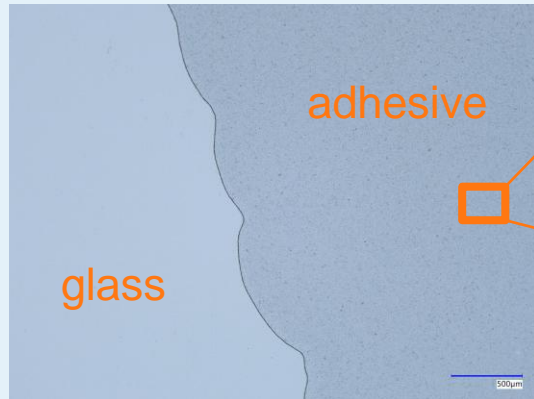
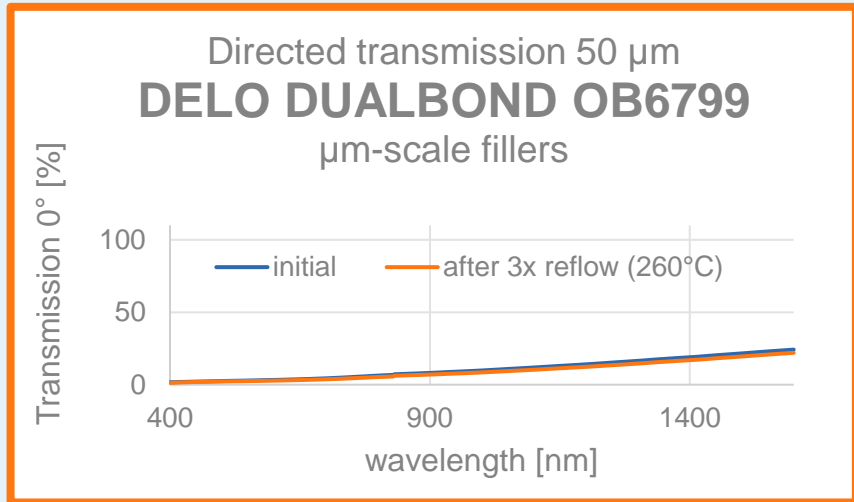
μm-sized SiO_2 fillers in epoxy-based adhesive



Nano scale vs. micro scale



OB6268 nano-sized fillers



OB6799 micro-sized fillers

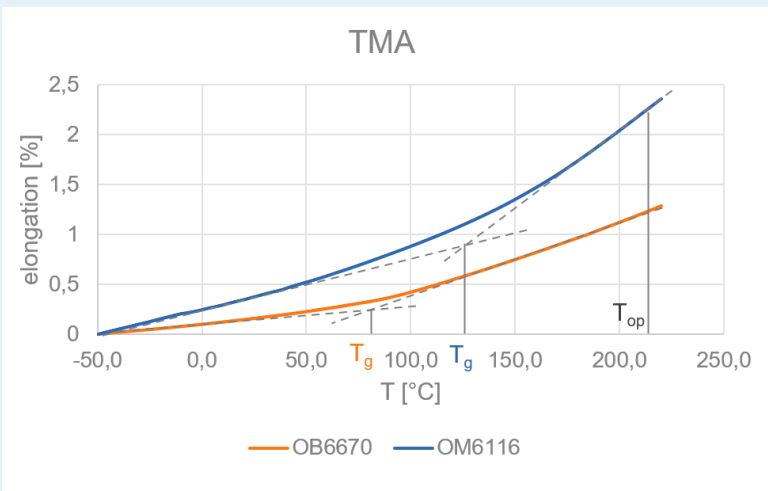


Temperature Impact

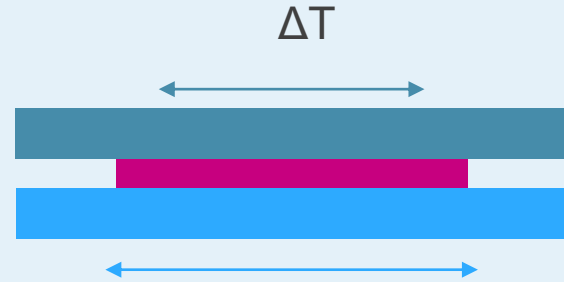
Misalignment

Why high T_g ?

- ▶ In general: $\alpha_2 > \alpha_1$
- ▶ More essential:
CTE @ T_{op} as low as possible



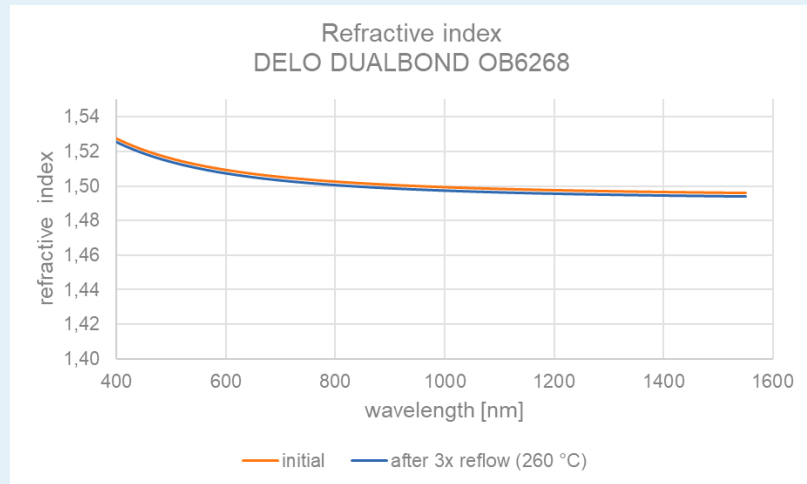
Delamination



- ▶ CTE mismatch: stress on adhesive
- ▶ Young's Modulus
- ▶ Adhesion strength

Optical reliability

▶ Refractive Index

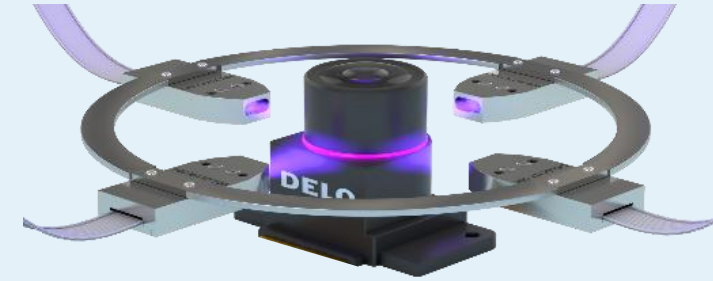
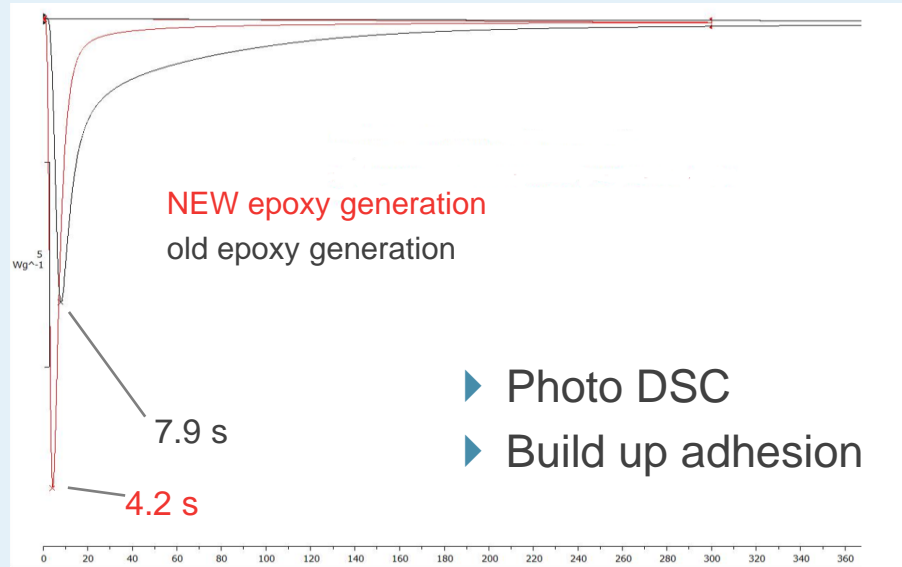


▶ Transmission

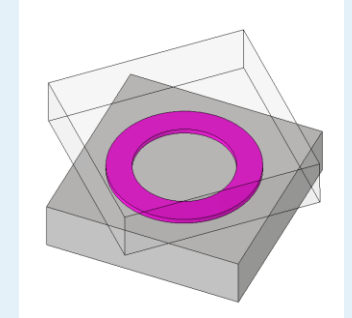




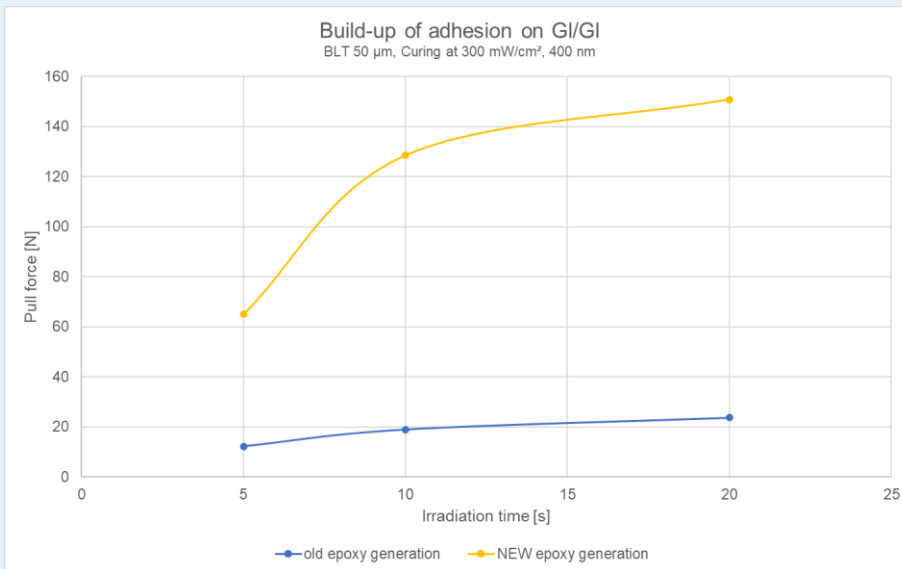
Curing speed



4-sided curing with DELOLUX504 (365 or 400 nm)



Crossed lap joints for pull-off test



Why does it matter?

- ▶ UPH
- ▶ More important: Post shrinkage





DELO μ lens to PIC Assembly

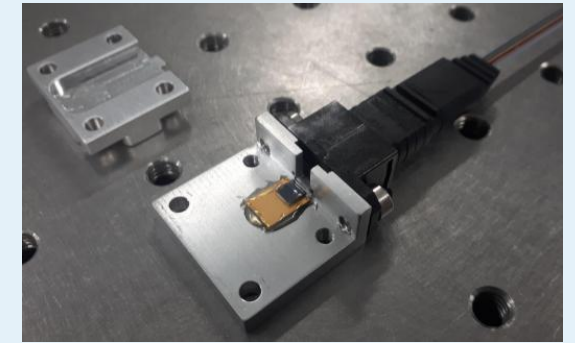
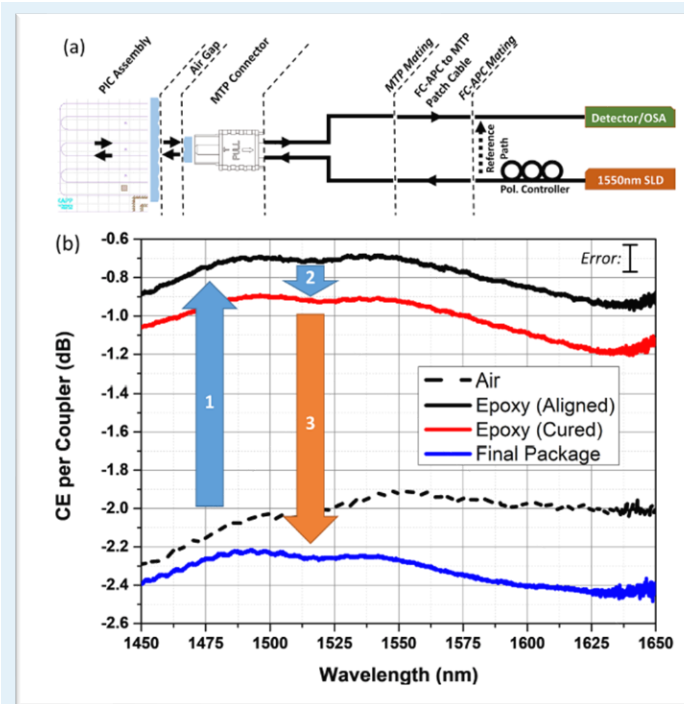
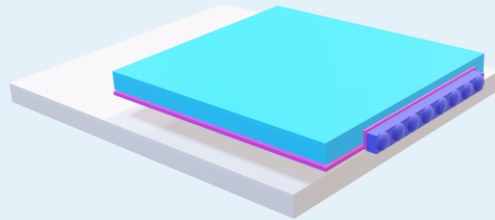
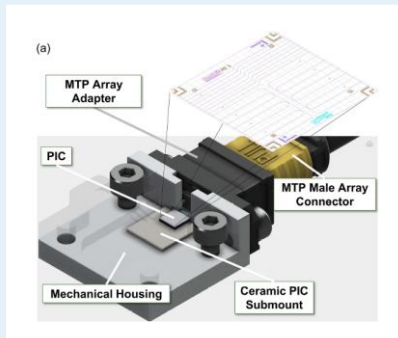


- ▶ iNEMI program: Module with Separable Single-Mode Expanded-Beam Optical Interface for Edge-Coupled PIC Optics



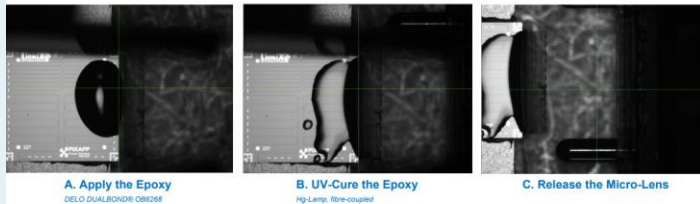
DELO DUALBOND OB6268

- 1) μ -lens to PIC (AA)
- 2) Submount to housing (AA)



- ▶ Only **0.2 dB loss** by shrinkage (2)
- ▶ 1.3 dB loss by final packaging (3) → not optimized

Micro-Lens Attachment – Lens Attachment



PIC Assembly Attachment

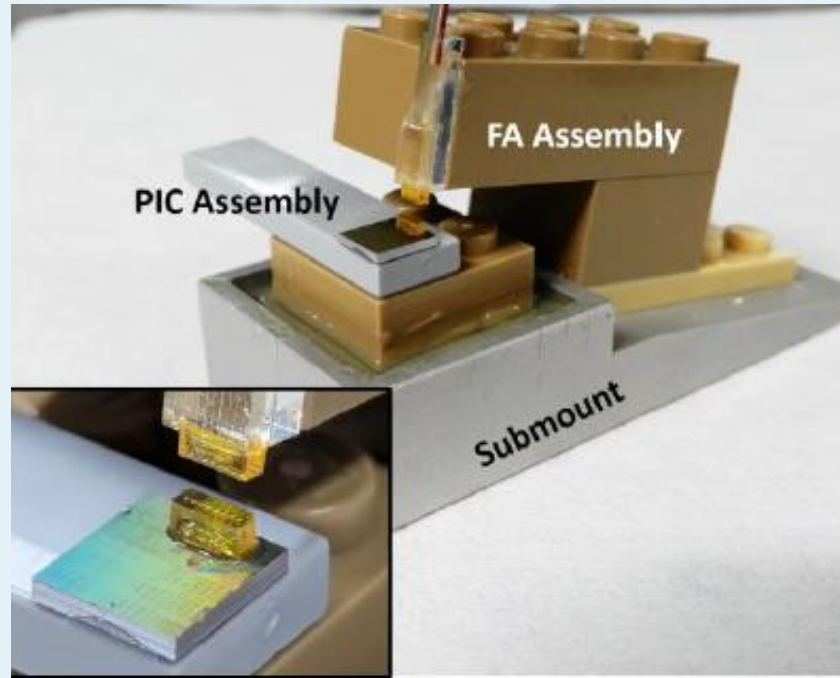
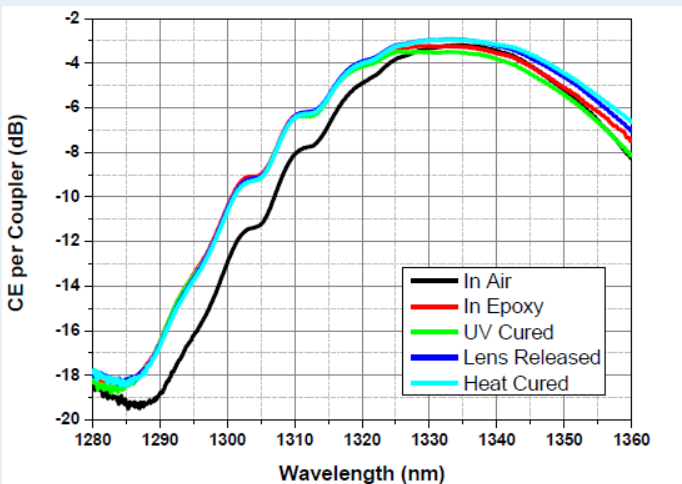
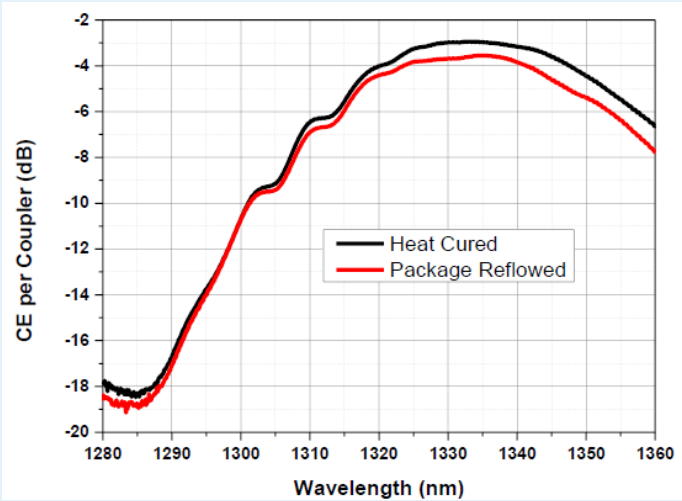


Demonstration of a Single-Mode Expanded-Beam Connectorized Module for Photonic Integrated Circuits

K. Gradkowski et al. Journal of Lightwave Technology Vol. 41, No. 11 (2023)

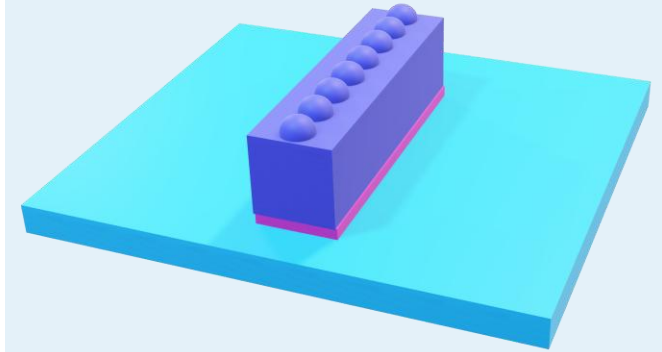


DELO μ lens to PIC Assembly



DELO DUALBOND OB6235

- 1) μ -lens to PIC (AA)
- 2) μ -lens to FAU (AA)



- ▶ **0.3 dB loss** by shrinkage
- ▶ **0.7 dB CE decrease per coupler** after reflowing the whole package



Solder Reflow Resistant Thermoplastic for Optical Coupling

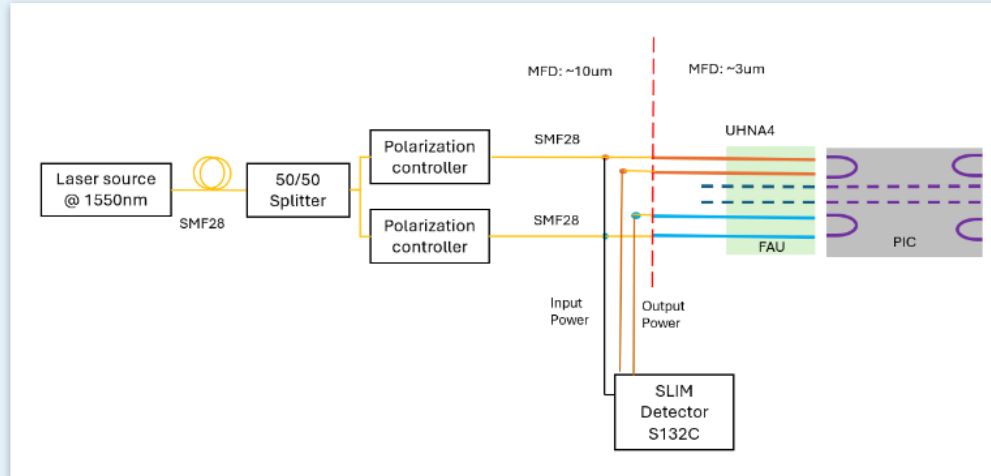
K. Gradkowski et al. IEEE Transactions on Components, Packaging and Manufacturing Technology (2024)



Outline

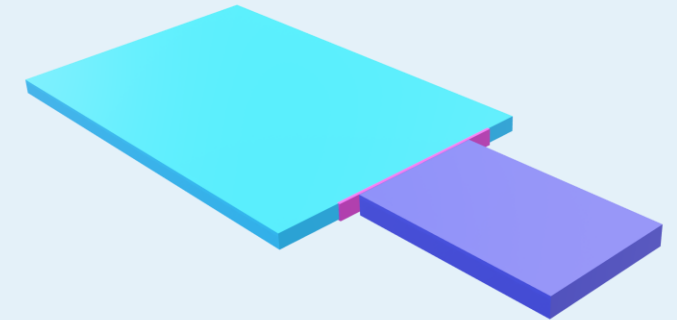
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- ▶ **Optical coupling evaluation**
- ▶ Wafer level photonics coupling solution
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Edge coupling – Fast curing epoxy

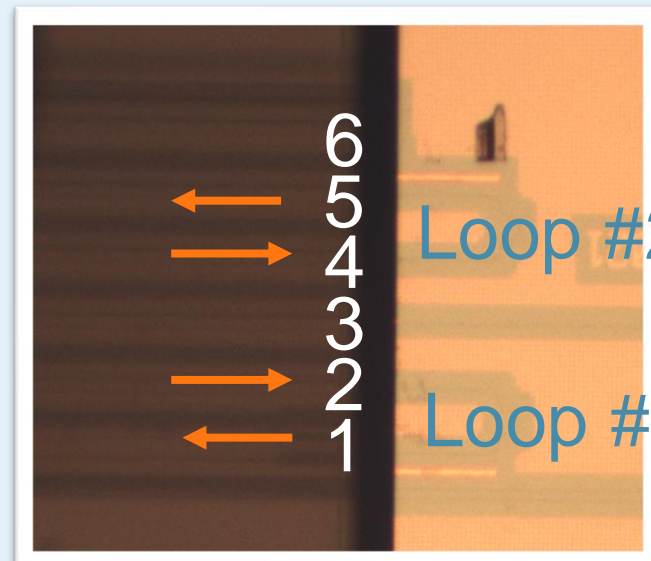
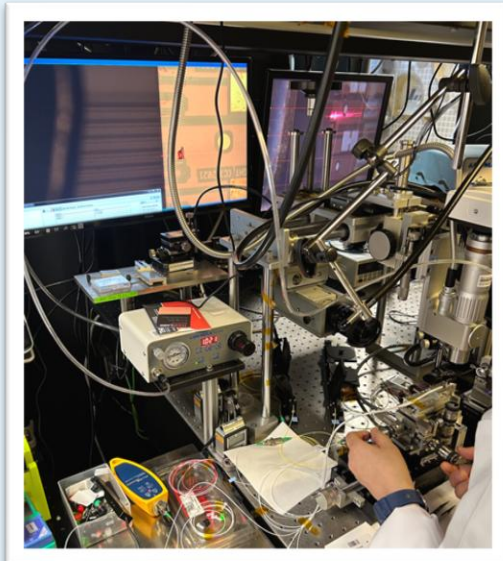


DELO DUALBOND D2

1) FAU to PIC



- ▶ Highly filled (nm)
- ▶ High T_g (172 °C)
- ▶ Very fast curing (Photo-DSC Peak 4.5 s)

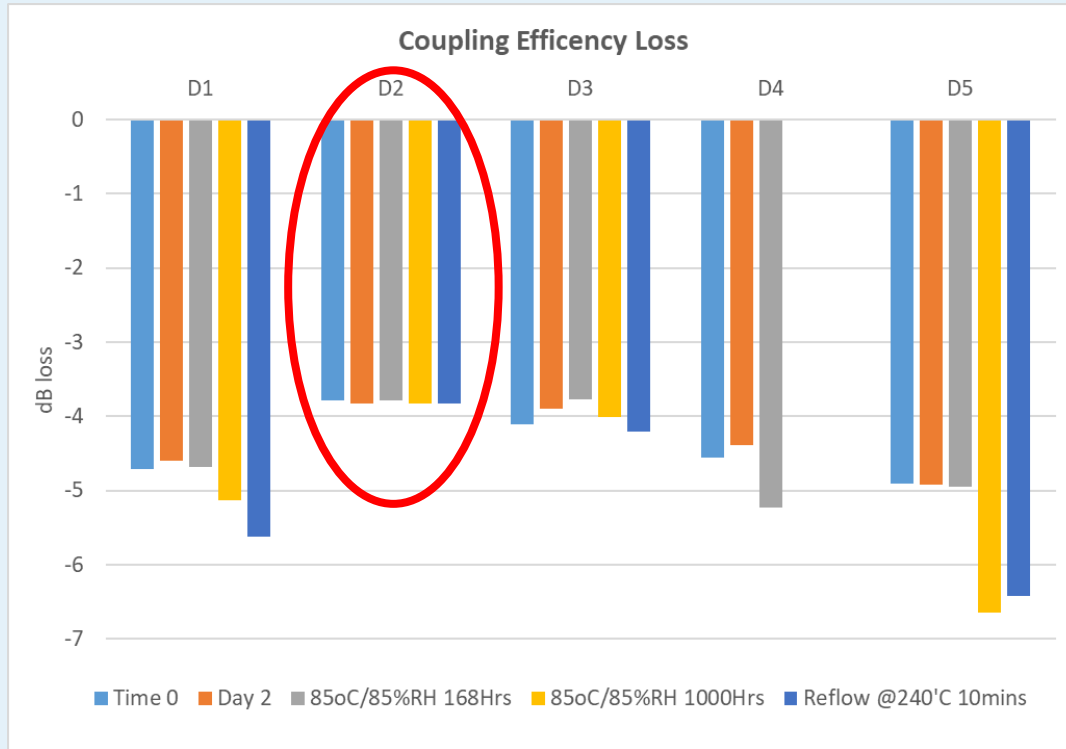
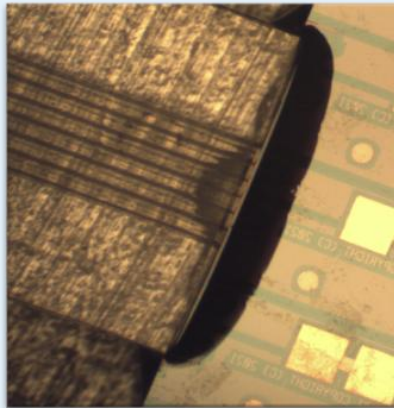
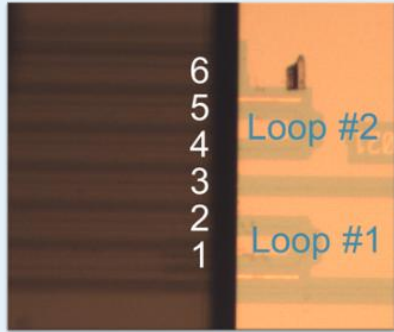


FAU to PIC edge-coupling

01091

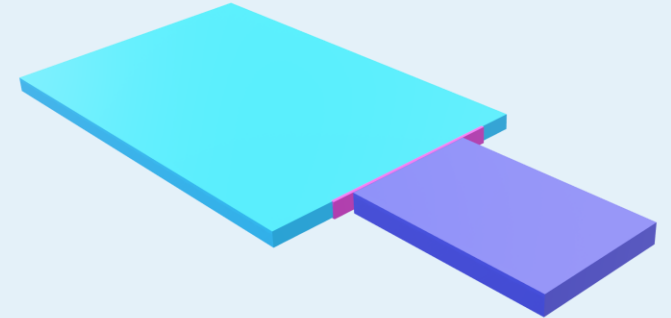


Edge coupling – fast curing epoxy



DELO DUALBOND D2

1) FAU to PIC



| | Coupling efficiency [dB] | |
|---------------------------|--------------------------|---------|
| | loop #1 | loop #2 |
| Before curing | -3.73 | -3.79 |
| After curing | -3.73 | -3.84 |
| After release | -3.73 | -3.84 |
| After 24 h | -3.76 | -3.81 |
| After 1000 h 85/85 | -3.72 | -3.94 |
| After Reflow 240'C 10mins | -3.74 | -3.90 |

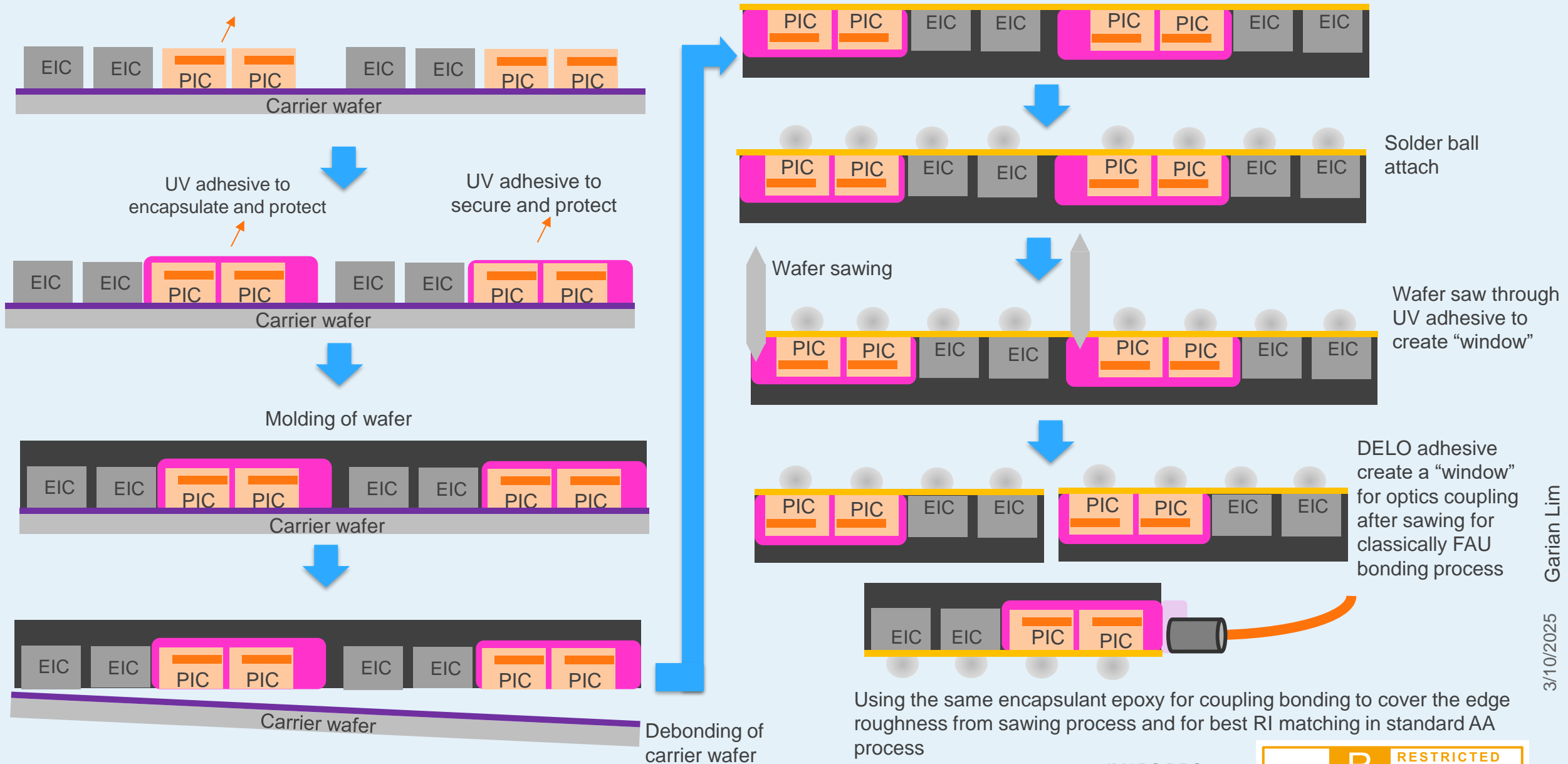
➔ High curing speed results in low postcuring
 ➔ Very low loss after rel.-testing



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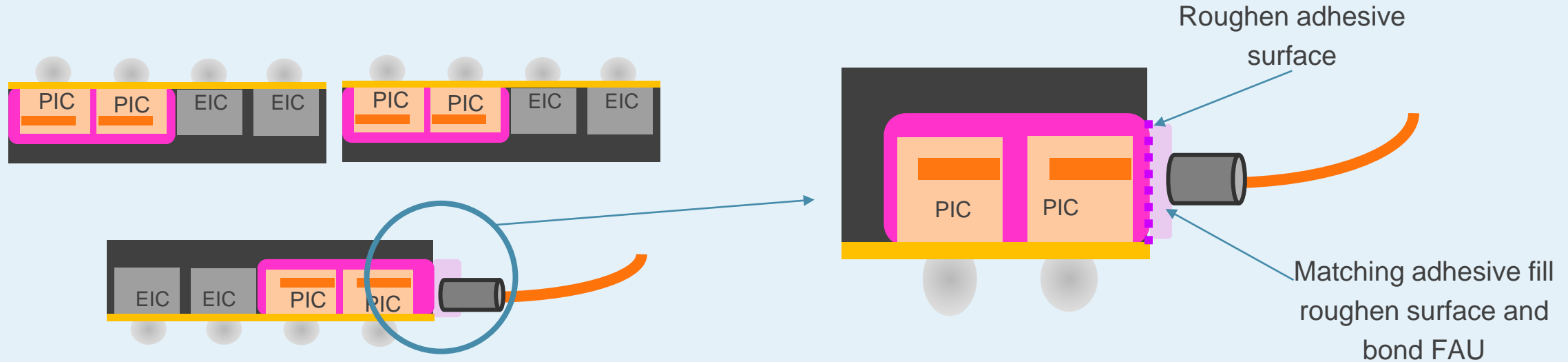


Wafer Level Photonics – Edge coupling concept



Garian Lim

3/10/2025

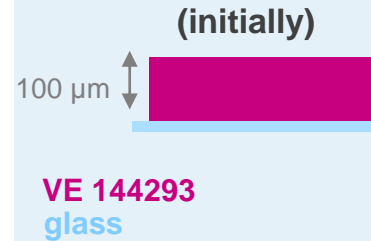
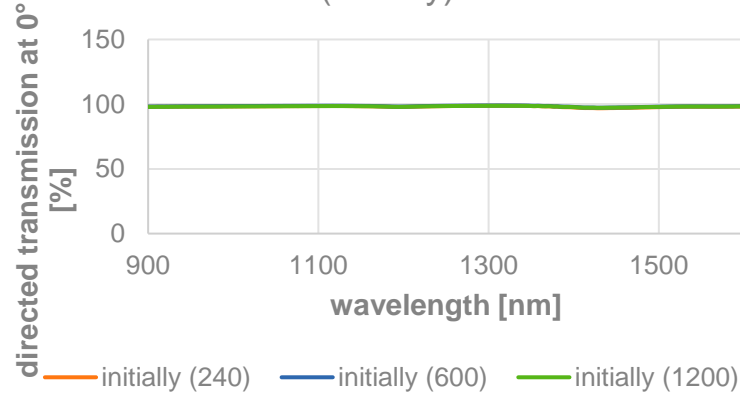


- ▶ Adhesive side-wall is roughened due to sawing or grinding process
 - » Reduce optical transmission and create reflection/refraction losses
- ▶ Matching adhesive used to bond and fill roughen surface
- ▶ Eliminate expensive and time-consuming polishing process
- ▶ Single step fiber bonding with coupling surface improvement
 - » Eliminate uneven surface due to processing
 - » Improve transmission and reduce losses

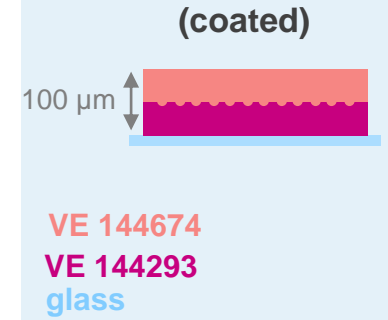
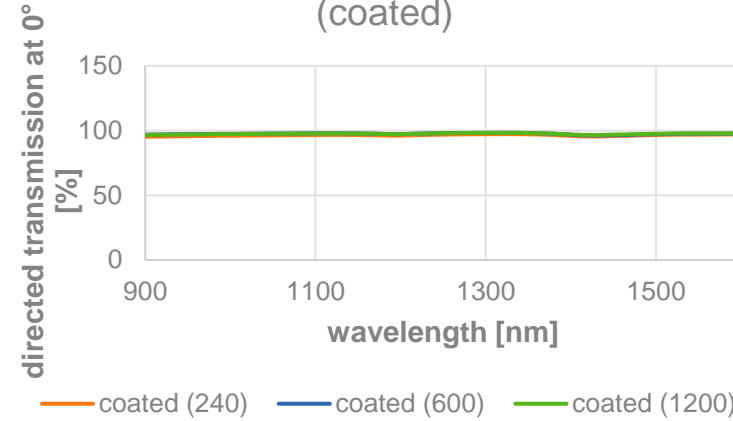


DELO DUALBOND VE 144293 & VE 144674

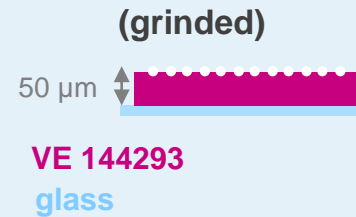
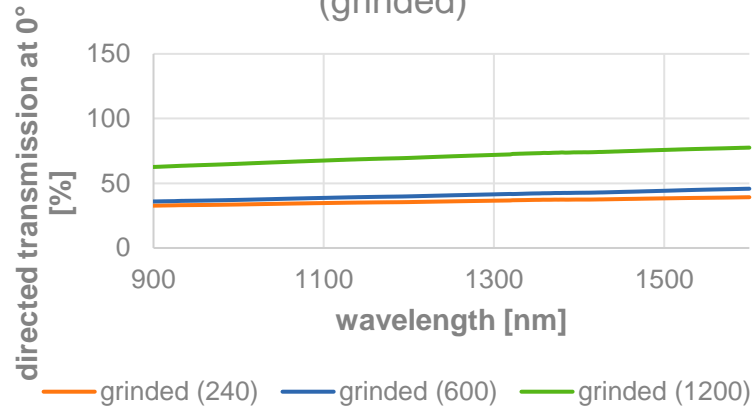
DELO DUALBOND VE 144293 (initially)



DELO DUALBOND VE 144293 (coated)



DELO DUALBOND VE 144293 (grinded)



| Transmission @ 1310 nm [%] | | | |
|----------------------------|-----------|---------|--------|
| grainsize | initially | grinded | coated |
| P240 | 98,8 | 36,6 | 97,3 |
| P600 | 99,0 | 41,6 | 98,3 |
| P1200 | 98,8 | 72,1 | 98,2 |

| Transmission @ 1550 nm [%] | | | |
|----------------------------|-----------|---------|--------|
| grainsize | initially | grinded | coated |
| P240 | 98,0 | 38,8 | 96,9 |
| P600 | 98,3 | 45,1 | 97,6 |
| P1200 | 98,2 | 76,7 | 97,8 |

➔ Matching adhesive can recover transmission lost



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Summary

- ▶ PIC packaging is technically challenging
- ▶ Adhesives play a crucial role
- ▶ Adhesives must be carefully selected matching the requirements (process & reliability)
- ▶ Adjusting of adhesive properties by chemistry and fillers
- ▶ DELO offers adhesive-solutions for various bonding applications (i.e. DELO DUALBOND OB6268 for optical coupling)
- ▶ We are open for collaborations!



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600**





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 Malaysia | Singapore | Thailand | USA



Discuss your project and get in contact
 with our team:
photonics@delo.de